

# **Power Spectrum Analysis**

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# Power Spectrum Analysis (PSA) Overview

- **Device frequency-domain responses** to dynamic stimuli
  - Use normal and **off-normal** biasing/detection
  - Produce repeatable frequency domain fingerprints
  - Comparison approach
- **Non destructive** and short acquisition times
  - typically < 15 seconds

## Applications

- **Supply chain risk management (SCRM) at the chip, board, and system levels:**
  - Determine if suppliers are providing us what we expect
- **Anomaly detection:**
  - Verify that parts, boards, and systems are un-modified, especially if they leave our possession
- **Reliability, failure/aging detection, and radiation effects/exposure detection**
- **Process monitoring**



# Different Distributors

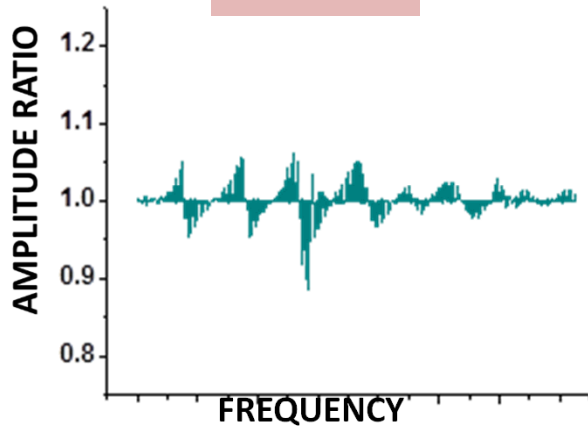
## Genuine and Counterfeit Parts

### PSA Spectra: XC4008E FPGA

**Distributor A**



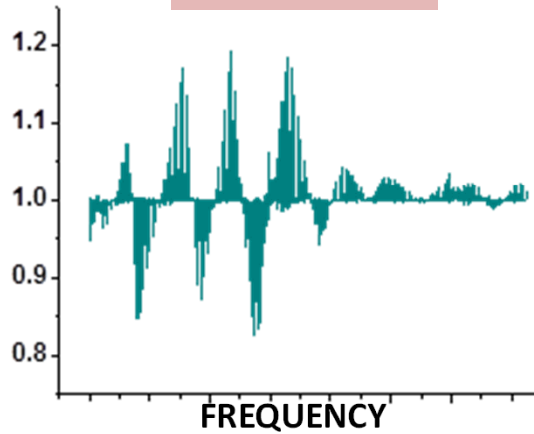
**Genuine**



**Distributor B**



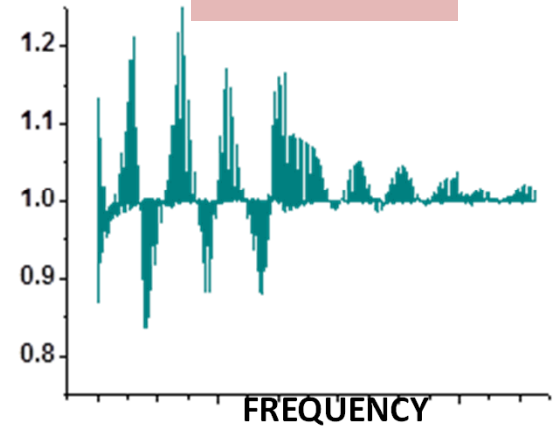
**Counterfeit**



**Distributor C**



**Counterfeit**





# Different Distributors: Genuine and Counterfeit Parts

## PCA of PSA Spectra of XC4008E FPGA

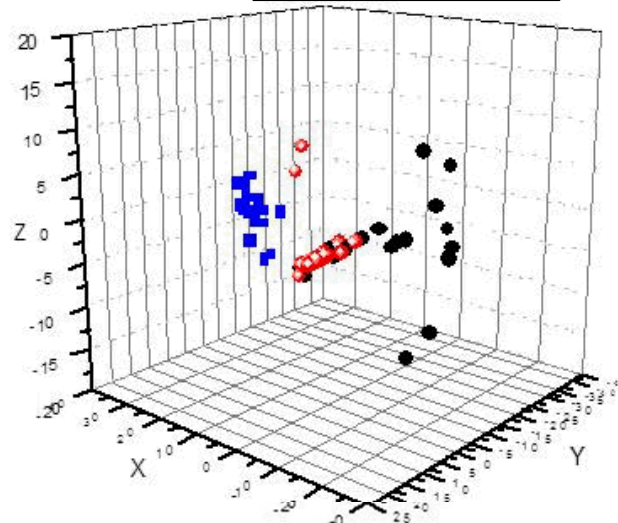
Distributor A population is separate from those of Distributor B/Distributor C

Distributor A samples have a more localized distribution

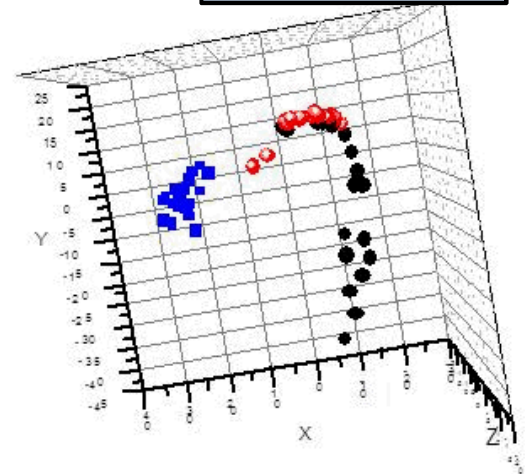
More scattering in Distributor C population

- Distributor A    **Genuine**
- Distributor B    **Counterfeit**
- Distributor C    **Counterfeit**

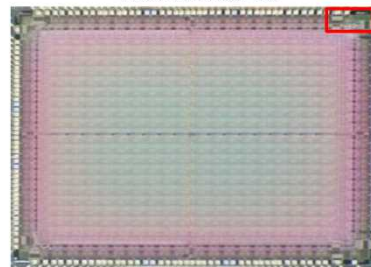
Perspective 1



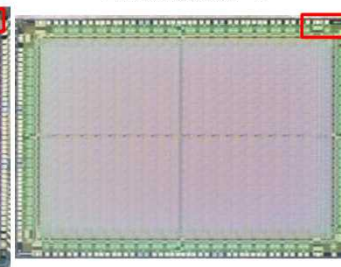
Perspective 2



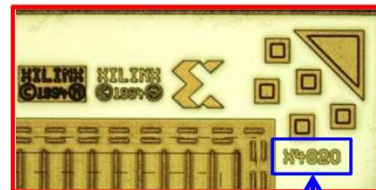
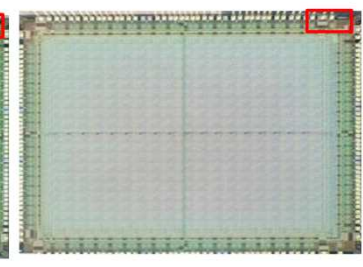
Distributor A



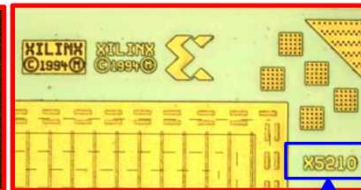
Distributor-B



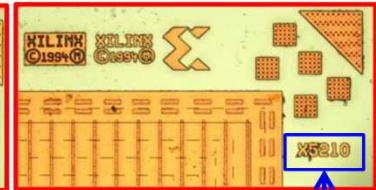
Distributor-C



X4820



X5210

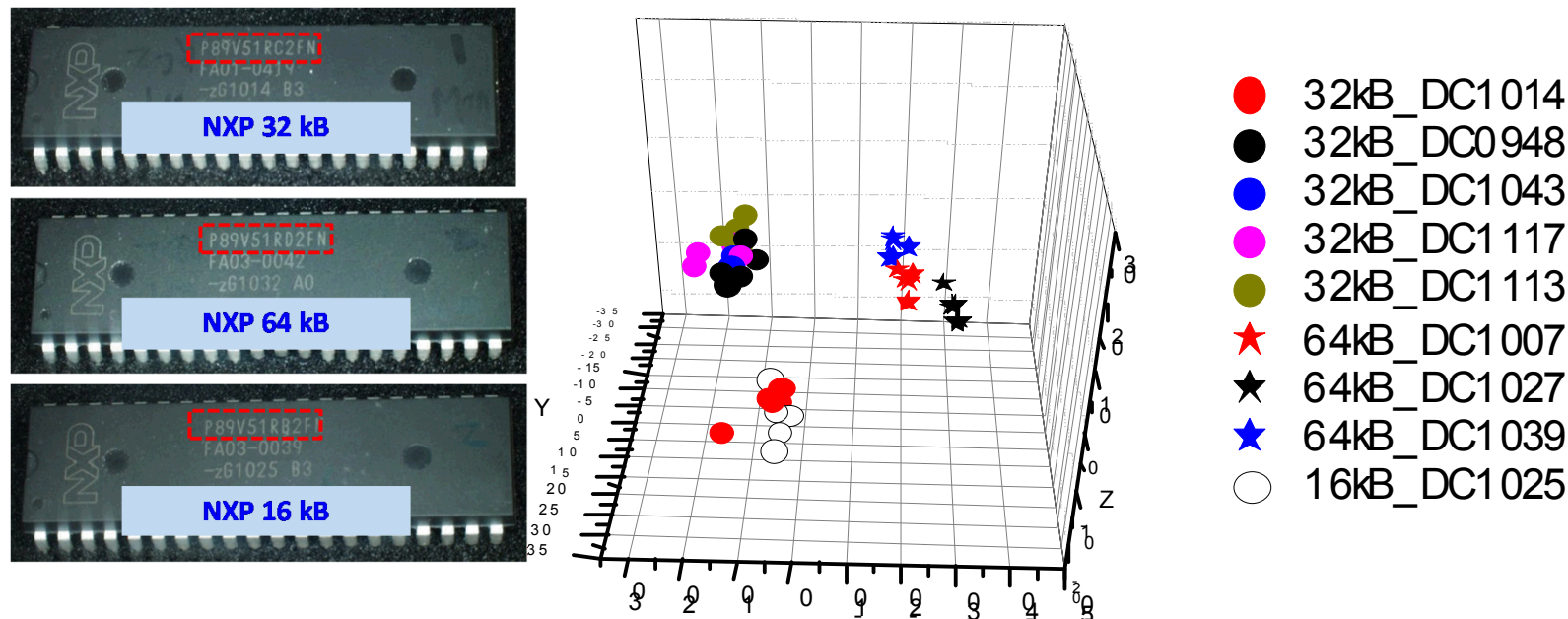


X5210



# Different Memory Sizes and Date Codes

## PCA of PSA Data of NXP Microcontrollers



- 32 kB samples show a bi-modal distribution with samples from date code 1014 appearing in a separate cluster
- 16 kB samples lie in the same cluster as 32 kB samples with date code 1014

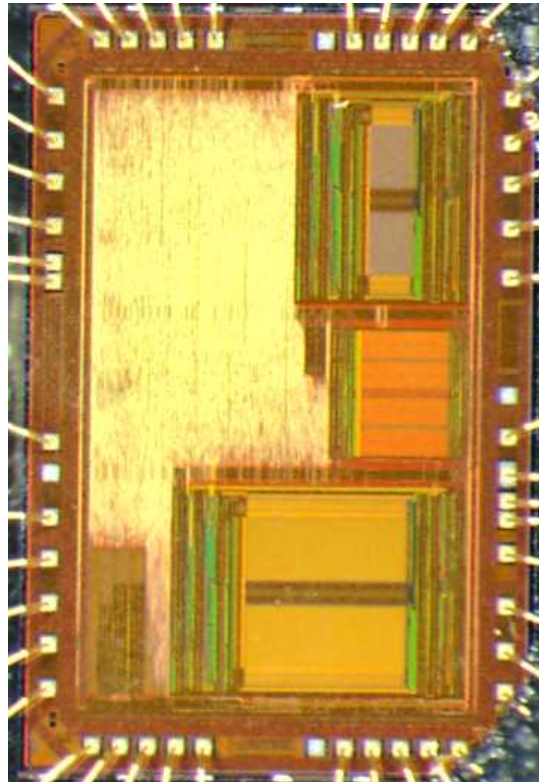
Note that PSA detected that 32kB (red) parts were the same as the parts marked as 16 kB. The next slide shows that the “16 kB” parts were really 32 kB.



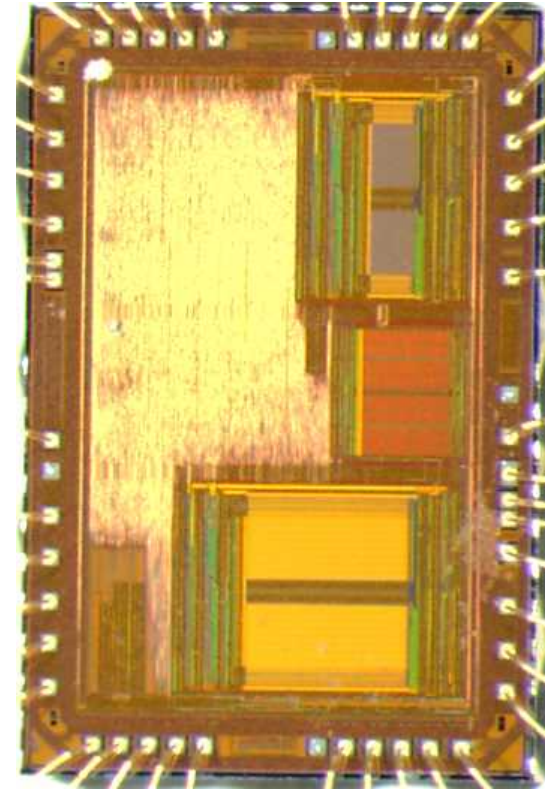
# Different Memory Size (32 kB versus 16 kB)

## Optical Images of NXP Microcontrollers

Device with 32 kB memory



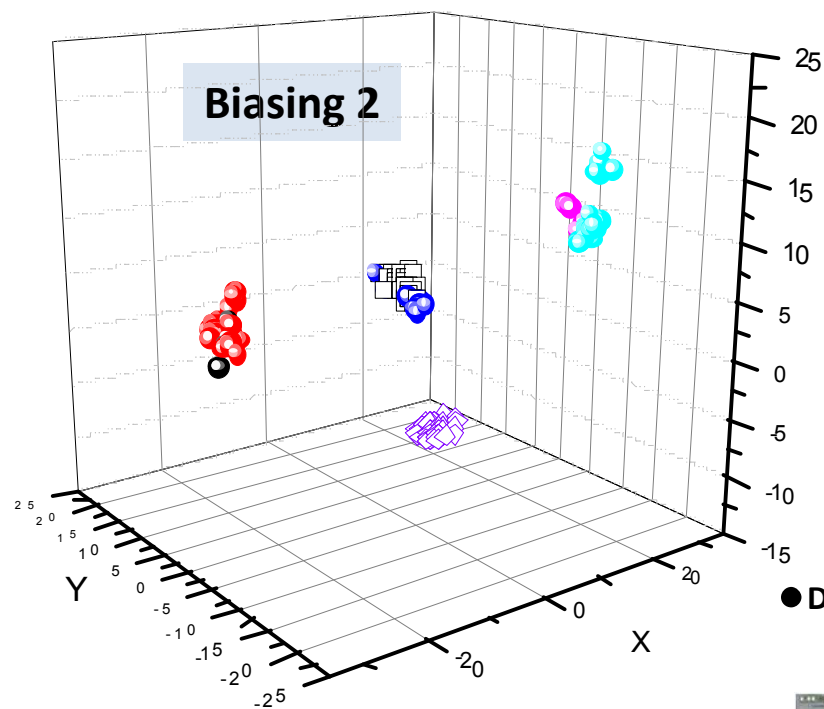
Device with 16 kB memory



- Same dice type used for 32 kB and 16 kB devices
- Devices have different ID codes
- 16 kB devices can be used as 32 kB devices by ignoring the ID code verification

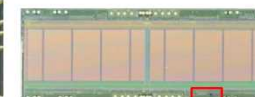
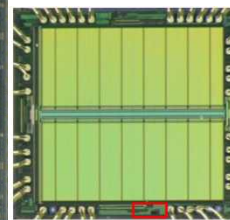
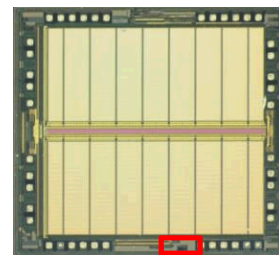


# Principal Component Analysis (PCA) of PSA Spectra of IDT71016SA10Y Samples



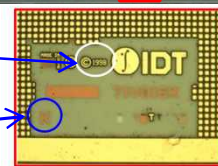
- Distributor A-1\_T9930P
- Distributor A-2\_T9944P
- Distributor A-3\_H0922P
- Distributor A-4\_H0216M
- Distributor A-5\_H0429M
- Distributor B\_H1324P
- ◇ Distributor C\_K0122M

◇ Distributor C K0122M    □ Distributor B H1324P    ● Distributor-A-1 T9930P



1998

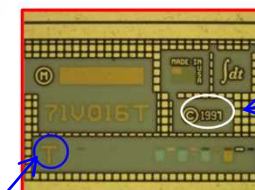
K



H

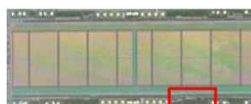


T

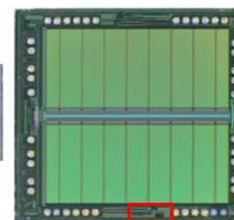


1997

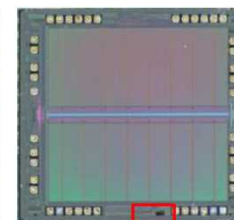
● Distributor-A-2 T9944P



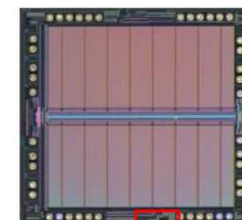
● Distributor-A-3 H0922P



● Distributor-A-4 H0216M

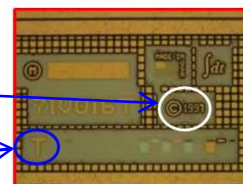


● Distributor-A-5 H0426M



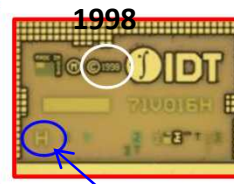
1997

T



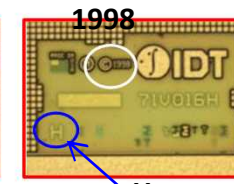
1998

H



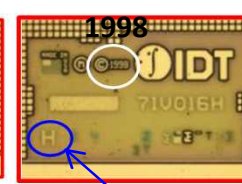
1998

H



1998

H





# Summary

**PSA is an electrical test to identify subtle device changes for counterfeit detection. Results so far have detected**

- **Counterfeit devices**
  - **Differences between counterfeit parts and genuine parts**
  - **Differences in manufacturers, foundries, features**
- **Aged devices (used parts)**
- **Irradiated parts**
- **Changes in processing**
- **Changes in packaging**

## Other PSA Studies

- **Used advanced modeling to understand PSA signatures**
- **Determined that PSA does not create latent damage/aging of devices being tested**